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# Hall and bend resistance of a phosphorene Hall bar

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The dependence of the Hall and bend resistances on a perpendicular magnetic field and on vacancy defects in a four-terminal phosphorene single layer Hall bar is investigated. A tight-binding model in combination with the Landauer-Büttiker formalism is used to calculate the energy spectrum, the lead-to-lead transmissions, and the Hall and bend resistances of the system. It is shown that the terminals with zigzag edge orientation are responsible for the absence of quantized plateaus in the Hall resistance and peaks in the longitudinal resistance. A negative bend resistance in the ballistic regime is found due to the presence of highi- and low- energy transport modes in the armchair and zigzag terminals, respectively. The system density of states, with single vacancy defects, shows that the presence of in-gap states is proportional to the number of vacancies. Quantized plateaus in the Hall resistance are only formed in a sufficiently clean system. The effects of different kinds of vacancies where the plateaus are destroyed and a diffusive regime appears in the bend resistance are investigated.

# I. INTRODUCTION

In pursuit of the next generation of nanodevices and to continue its downscaling, scientists have started to focus their attention on two-dimensional (2D) materials due to their nanoscale thickness<sup>1</sup>. Among these materials, black phosphorus, which in ambient is the most stable phosphorus crystal at room temperature and pressure, has drawn a lot of attention recently due to its unique electronic properties which depend on the number of layered phosphorene<sup>2,3</sup>. Black phosphorus is a layered material where each individual atomic layer is held together by van der Waals interactions $^{4-6}$ . This allows the construction of phosphorene devices with an arbitrary number of layers<sup>6,7</sup>. Each phosphorus atom in a phosphorene monolayer is bounded via  $sp^3$  hybridization forming a puckered lattice structure. Unlike other 2D layered materials, black phosphorus shows interesting properties such as high carrier mobility<sup>3,6</sup>, anisotropic opticalconductance<sup>8,9</sup>, and a band gap dependence on the number of layers<sup>9,10</sup>, ranging from 0.3 eV for bulk and 1.5 eV for monolayer phosphorene. This material also has a good on/off switch, which makes it a good candidate for field effect transistor (FET) devices  $^{11,12}$ .

The above mentioned phosphorene FET devices were analyzed at room temperature through Hall measurements with mobility up to ~  $1000 \text{cm}^2 V^{-1} \text{s}^{-1}$ . It was found that the carrier mobility is limited by charge impurities at low temperature<sup>12</sup>. It is important to mention that Hall measurements can accurately determine the carrier density, electrical resistivity, and the mobility of carriers in semiconductors<sup>13</sup>. It is well known that 2D electron gas submitted to a perpendicular magnetic field leads to the formation of Landau levels, and as a consequence it leads to the formation of quantized levels and oscillations in the Hall and longitudinal conductivity/resistance<sup>13-15</sup>. With the application of a perpendicular magnetic field it is also possible to focus electrons injected from a narrow injector allowing the study of different properties of a material  $^{16}$  in such a magnetic focusing experiment.

The presence of defects is almost inevitable in materials. In particular, vacancies in phosphorene were reported to exhibit a highly anisotropic and delocalized charge density, with intrinsic vacancies resulting in ingap resonance states 17-19. In the absence of a magnetic field, the effects of different types of vacancies in phosphorene monolayer were theoretically investigated in multiterminal systems showing that the presence of atomic defects decrease (an increase) the longitudinal (transverse) conductance<sup>20,21</sup>. Studies on graphene showed that vacancy disorder can cause the appearance of new states in the Landau spectrum, which depend on the type and density of vacancies, which can be observed in the bend resistance and the density of states  $(DOS)^{22}$ . To provide insights on how vacancies affect the transport properties of phosphorene, we analyze the different resistances in a Hall bar configuration.

In this paper, the problem of magnetotransport in multiterminal phosphorene monolayer is addressed. This will be done by studying the resistance of a four-terminal Hall bar system in the presence of a perpendicular magnetic field. This paper is organized as follows. First, we present in Sec. II the theoretical formalism to calculate the different resistances in a Hall bar using the Landauer-Büttiker formalism<sup>23</sup> and the tight-binding model to describe the phosphorene lattice<sup>24</sup>. In Sec. III, the results for a pristine Hall bar with an applied perpendicular magnetic field is presented. In Sec. IV, the effect of vacancies on the DOS and the transport properties are investigated. The perspectives and conclusions are presented in Sec. V.

#### A. Phosphorene



FIG. 1. The phosphorene nanoribbon along the xy plane (a), and the representation in the zx plane (b). The different hoppings are shown in (a) and the rectangular shaded box gives the unit cell. The coloured dots refer to P atoms belonging to different sublattices.

The unit cell of phosphorene contains four atoms, with  $a_1 = 3.32$ Å and  $a_2 = 4.38$ Å being the primitive vectors and a = 2.22Å and  $\theta = 96.79^{\circ}$  are the in-plane bond length and bond angle, see Fig. 1. For our numerical simulations, we use the tight-binding model with five-hoppings as introduced in Ref. [<sup>24</sup>]. The tight-binding Hamiltonian is given by

$$H = \sum_{i} \epsilon_{i} n_{i} + \sum_{i \neq j} t_{ij} c_{i}^{\dagger} c_{j}, \qquad (1)$$

where the sums run over the lattices sites,  $c_i^{\dagger}(c_j)$  is the creation (annihilation) operator,  $\epsilon_i$  is the electron onsite energy,  $t_{ij}$  are the elements of the hopping matrix. Because all phosphorene atoms are equivalent, we may set the on-site energy to zero. The five hopping parameters are given by  $t_1 = -1.220$  eV,  $t_2 = 3.665$  eV,  $t_3 = -0.205$  eV,  $t_4 = -0.105$  eV, and  $t_5 = -0.055$  eV. They describe the band structure of phosphorene in the low-energy regime and agree with the one obtained from DFT-GW calculations<sup>24</sup>.

The peculiar electronic properties of the phosphorene band structure is shown in Fig. 2 (a) for the armchair edge and Fig. 2(b) for the zigzag edge, both with width W = 50 nm. The main difference between the two orientations is the presence of a quasi flat band within the band gap in the nanoribbon with zigzag edges resulting in metallic behavior<sup>25,26</sup>, while the band structure for the armchair terminal is semiconducting. The corresponding DOS are also shown.

The phosphorene monolayer is modelled using a four band tight-binding model, but can be reduced to a twoband model due to the symmetry between the sublattices A and  $D^{27}$  [see Fig. 1]. In this reduced form the number of atoms in sublattices, labeled A and B for convenience, are  $N_A$  and  $N_B$ . For pristine phosphorene monolayer (without defects),  $N_A = N_B$  (sublattice symmetry). In this system, vacancies are introduced by randomly removing atoms from the phosphorene lattice, eliminating



FIG. 2. Phosphorene nanoribbon band structure and density of states for armchair (a), and zigzag (b) edges. The nanoribbons correspond to the different leads in the investigated Hall bar with width 50 nm.

the on-site energy and the hopping of the removed atom. Figure 3 shows sections of the defective phosphorene Hall bar with three types of atomic vacancies: A mono vacancy (MV) where a single sublattice atom is removed, a type-I double vacancy (DV1) where an atom and its neighbor sublattice atom on a different z-plane are removed, and a type-II double vacancy (DV2) where the neighbor sublattice atom is removed on the same z-plane.

In the MV case, where only one of the sublattice atoms is removed, the sublattice symmetry is broken  $(N_A \neq N_B)$ . For the type-I DV, where two sublattice atoms are removed, being two A (or two B), the sublattice symmetry is also broken  $(N_A \neq N_B)$ . However for type-II, where one A and one B are removed, the symmetry is preserved  $(N_A = N_B)$ .



FIG. 3. The disorders in phosphorene Hall bar for monovacancies (MVs), double vacancy type I (DV1) and type II (DV2). Only half of the Hall bar is shown.

#### B. Hall bar

The Hall device is schematically presented in Fig. 4. It is a four-terminal Hall bar system with an applied magnetic field in the z direction, where the magnetic field is introduced through the vector potential.

The Landau gauge  $\vec{A}_H = -By\vec{e}_x$  is one of the standard gauges which works only for leads with translational sym-

metry in x direction. For y translational symmetry, we need to change it to the gauge  $\vec{A}_V = Bx\vec{e}_y$ . The change from one gauge to the other is done smoothly by implementing the scalar function f(x, y) which rotates the vector potential  $\vec{A'} = \vec{A} + \vec{\partial}f$ , where f is defined as<sup>22,28</sup>



FIG. 4. Schematic representation of the Hall bar. The modified vector field  $\vec{A'}(x, y)$  is shown by the arrows. In the system, contacts 1 and 3 represent the armchair terminals while contacts 2 and 4 the zigzag terminals.

$$f(x,y) = Bxy\sin^2\theta + \frac{1}{4}B(x^2 - y^2)\sin 2\theta.$$
 (2)

Here  $\theta$  is the angle between the two leads (in our system  $\theta = \pi/2$ ). To apply f(x, y) only in the main region we multiply it by a smooth step function  $\epsilon_i(y) = \frac{1}{2} [1 + \tanh(2(y - y_0)/d)]$ , which is non-zero only close to the lead *i*.  $y_0$  is the crossover position and *d* is the width of the crossover region. For our numerical calculations we took  $y_0 = W$  and d = W/5, where  $W = 50 \text{ nm}^{22}$ . The modified magnetic field is then implemented on the tight-binding Hamiltonian Eq. (1) by making use of the Peierls substitution  $t_{ij} = t_{ij}e^{i\phi_{ij}}$ . The Peierls phase is then described as

$$\phi_{ij} = \int_{\vec{r_j}}^{\vec{r_i}} \vec{A} \cdot d\vec{r}.$$
 (3)

The resistances are calculated using Landauer-Büttiker formula<sup>29</sup>. The four-terminal resistance in a cross-shaped structure is given by

$$R_{mn,kl} = \frac{h}{2e^2} \left( \frac{T_{km}T_{ln} - T_{kn}T_{lm}}{D} \right), \qquad (4)$$

where h is the Planck's constant.  $R_{mn,kl}$  is the resistance with the voltage being measured between the leads k and l when the current is driven into contact m and taken out from contact *n*. In Eq. (4),  $D = (\alpha_{11}\alpha_{22} - \alpha_{12}\alpha_{21})S$ , with

$$\begin{aligned} \alpha_{11} &= [(T_{21} + T_{31} + T_{41})S - (T_{14} + T_{12})(T_{41} + T_{21})]/S, \\ \alpha_{12} &= (T_{12}T_{34} - T_{14}T_{32})/S, \\ \alpha_{21} &= (T_{21}T_{43} - T_{41}T_{23})/S, \\ \alpha_{22} &= [(T_{12} + T_{32} + T_{42})S - (T_{21} + T_{23})(T_{32} + T_{12})]/S, \end{aligned}$$

where  $S = T_{12} + T_{14} + T_{32} + T_{34}$ , and  $T_{ij}$  is the transmission probability from lead j to lead i. The resistances given by Eq. (4) satisfy the relation  $R_{mn,lk} = R_{nm,kl}$  and the reciprocity relation  $R_{mn,kl}(B) = R_{kl,mn}(-B)^{29}$ . In this paper we are also going to analyze the longitudinal resistance defined as  $R_{13,13}$  ( $R_{24,24}$ ), which represents the resistance between the two opposite armchair (zigzag) terminals. This schematic can also be calculated, in a first approximation<sup>30</sup>, by the analogous two-terminals systems, where the resistance is simply proportional to the transmission between the terminals<sup>13,30</sup>.

The probabilities  $T_{ij}$  are numerically calculated using KWANT<sup>31</sup>, a software package for numerical calculation of tight-binding systems with emphasis on quantum transport. It uses a matching wave-function approach<sup>32</sup> to calculate the transmission of an *n*-propagating mode in a contact terminal to the *m* mode in another contact. This formulation is mathematically equivalent to the non-equilibrium Green's function but was found to be numerically more stable<sup>31</sup>.

# **III. PRISTINE PHOSPHORENE HALL BAR**

Due to the anisotropy of the lattice, the Landau level splitting depends strongly the orientation and on the edge type of the phosphorene nanoribbon<sup>8,26</sup>. This dependency is shown in Fig. 5, where the electron energy spectrum for the armchair (ac) and zigzag (zz) nanoribon is plotted against the magnetic field, for nanoribbons with width W = 50 nm. For the zigzag orientation the effective electron mass is much smaller than the one for the armchair nanoribbon. That is the origin of the different spacing and magnetic field dependency of the Landau levels<sup>8,26</sup>.

Next, we analyze the resistances for Fermi energy near the intersecting points depicted in Fig. 5. The Hall  $(R_{13,42})$  and bend  $(R_{14,23})$  resistances were calculated for a Hall bar with terminals size 50 nm (with a total of 342384 atoms in the system). Figure 6 shows the resistance dependence on the Fermi energy  $(E_F > 0$  for electrons and  $E_F < 0$  for holes) for two different values of the applied magnetic field (5T and 10T). As the energy approaches the edges of the band, one can see the Hall resistance goes to infinity while the bend resistance goes to zero. The transition between two plateaus in the Hall resistance indicate the points where the Fermi energy crosses a semiconductor transverse mode (see Fig. 5) formed due the presence of magnetic field. Notice that



FIG. 5. The phosphorene energy levels for nanoribbons as function of magnetic field. The nanoribbons with width  $W_{ac} = 50$  nm and  $W_{zz} = 50$  nm correspond to the semi-infinite leads in the Hall bar. The points in the figure indicate the intersection of the Fermi energy  $(E_F)$ with the Landau levels.

at such points the bend resistance exhibits a negative dip. Another interesting phenomena is the presence of negative values in the bend resistance, indicating a ballistic regime (the ballistic regime will be discussed further when analyzing the resistances as a function of magnetic field).



FIG. 6. Hall  $(R_{13,42})$  and bend  $(R_{14,23})$  resistance dependency on the Fermi energy for two different values of the magnetic field.

To study the effect of the ribbon orientation the longitudinal resistances  $R_{13,13}$  and  $R_{24,24}$  are shown in Fig. 7. These resistances were calculated using the two-terminal relation for the resistances, which is just the inverse of the transmission between the two opposite terminals. Due to the anisotropic spectrum in phosphorene, one would expect that  $\sigma_{xx} < \sigma_{yy}$ , leading to  $R_{13,13} > R_{24,24}$ , but for Hall bar, the opposite happens. This is due to the presence of a scattering region in the Hall bar, that affects the conductivity making  $\sigma_{xx} > \sigma_{yy}$  and also  $R_{13,13} < R_{24,24}$ , as explained in Ref.  $[^{21}]$  for a cross-shaped phosphorene nanoribbon.



FIG. 7. Longitudinal resistance, measured for the armchair terminals  $(R_{13,13})$  and for the zigzag terminals  $(R_{24,24})$ , varying with the Fermi energy for two different values of the magnetic field.

Next, we investigate the different resistances as a function of the magnetic field for a fixed Fermi energy. It is well known that as the magnetic field increases, the Fermi energy crosses the semiconductor (armchair) transverse modes, resulting in well defined plateaus in the Hall resistance<sup>8</sup>. In the system studied here, this behavior is clear for  $E_F = 0.345$  eV and 0.34 eV (Figs. 8 and 9). However, for  $E_F = 0.363$  eV (Fig. 10) the plateaus in the Hall resistance are almost absent for a weak magnetic field. This can be explained by looking at Fig. 5. The Fermi energy  $E_F = 0.363$  eV is near to a zigzag transverse mode, which is almost magnetic-field independent<sup>8</sup>. Due to the metallic character, zigzag terminals induce scattering between the transport modes, not allowing the formation of quantized plateaus in the Hall resistance<sup>21</sup>. However, as the magnetic field increases, the energy of the zigzag Landau level differs from the Fermi energy, and the plateaus on the Hall bar are recovered.

The ballistic regime observed in Fig. 6 becomes more evident when analyzing the magnetic-field dependency reported in Figs. 8-10. The bend resistances in Figs. 8-10 are plotted in panel (a) (blue curve) which goes to zero as the magnetic field increases. A negative bend resistance indicates that the electron trajectory does not bend to the closer non-axial terminal<sup>33,34</sup>. We can understand this negative value by considering the definition of the four terminal resistance as  $R_{ij,km} = V_{km}/I_{ij}^{29}$ . For  $R_{14,23}$ , we have  $V_{23} = V_2 - V_3$ , indicating that  $V_{23} < 0$ , as  $V_2$  is a zigzag (lower energy) terminal and  $V_3$  is an armchair (high energy) terminal. Even though the bend resistance approaches zero, one can still see peaks in the resistances, indicating an increase in the transmission between axial terminals. These peaks happens whenever the Fermi energy cross an armchair transverse mode indicating an increase in the xx conductivity.



FIG. 8. (a) Hall (black), bend (blue) and (b) longitudinal (blue) resistances for a pristine phosphorene Hall bar for  $E_F = 0.345$  eV. The vertical dashed lines mark the points where the Fermi energy crosses the armchair Landau levels.

As stated before the  $R_{24,24}$  is larger than  $R_{13,13}$ , and they increase with different rates as the magnetic field increases. Figures 8-10 also show that for strong magnetic fields, the bend resistances go to zero while  $R_{24,24}$ takes larger values. Another peculiar behavior for  $R_{13,13}$ is noticed when the Fermi energies 0.345 eV and 0.35 eV cross the zigzag transverse mode (respectively at ~ 8.0T and ~ 8.60T). When that happens, a peak appears in  $R_{13,13}$ .

To understand the appearance of these peaks, Fig. 11 shows the magnetic-field dependency of the different transmissions probabilities between the leads for  $E_F = 0.345$  eV. An expected behavior is the decrease of  $T_{ij}$  between two counterclockwise terminals as the magnetic field increases. The transmission between the two arm-chair terminals suddenly increases as the transmission



FIG. 9. (a) Hall (black) and bend (blue) and (b) Hall (black) and longitudinal (blue) resistances for the pristine phosphorene Hall bar for  $E_F = 0.35$  eV. The vertical dashed lines marks the points where the Fermi energy crosses the armchair Landau levels.

with the next counterclockwise zigzag transmission decreases. This behavior is an indication of the induced transport-mode scattering by the zigzag terminals. Also, the reflection probability of the zigzag transport modes increase with magnetic field.

## **IV. EFFECT OF VACANCIES**

Figure 12 shows the DOS for a phosphorene Hall bar with MVs and DVs type I and II (see Sec. II). To get reasonable statistics the DOS was averaged over ten samples where the vacancies are randomly distributed. The number of vacancies is related to the quantity  $n_x$ , which is defined as the ratio between the atoms removed from the lattice and the total number of atoms. The peaks shown in Fig. 12 for the MV and DV2 systems are due to in-gap states. The intensity of the DOS is proportional to the number of defects<sup>18,35</sup>.

Although there are no transport modes inside the gap, the in-gap defect states can affect the system's conductivity via vacancy scattering<sup>20,36</sup>. This is shown in Figs. 13, where the Hall and bend resistances are plotted against the Fermi energy for two different values of vacancy density with an applied magnetic field B = 10 T. Each resistance was obtained as an average  $R = \sum_{i}^{N} R_i/N$ , for N = 10 random samples. For  $n_x = 0.01\%$ , we can still



FIG. 10. (a) Hall (black), bend (blue) and (b) Hall (black) and longitudinal (blue) resistances for the pristine phosphorene Hall for  $E_F = 0.363$  eV. The vertical dashed lines mark the points where the Fermi energy crosses the armchair Landau levels.



FIG. 11. The transmission probability from the leads 1 (a) and 4 (b) to the other leads. The local current density is calculated for specific magnetic fields 8.0, 8.4, 8.7 and 10.0 T, respectively (c), (d), (e) and (f). Density values were normalized. The Fermi energy is  $E_F = 0.345$  eV.



FIG. 12. DOS of the phosphorene Hall bar for pristine and for three types of disorder with  $n_x = 1\%$ .



FIG. 13. Hall and bend resistances for the phosphorene Hall bar with different densities of vacancies for B = 10T. The bend resistances were multipled by a defined factor to increase its visibility. The grey vertical lines mark the place where the Fermi energy crosses an armchair transverse mode.

see the presence of plateaus in the Hall resistance, but it vanishes for  $n_x = 0.05\%$  due to scattering.

Another interesting result is the presence of welldefined peaks in the bend resistance, peaks that were not present in the pristine case (see Fig. 8). This indicates that already for small vacancy density the system is in the diffusive regime. These peaks, unlike in the case in graphene<sup>22</sup>, are not due to localization states. They occur when the Fermi energy cross an armchair transverse mode and are related to the increase of diffusion due to the vacancy scattering. Also, this effect is more evident for MV disorder, as for the same vacancy density the MV are more spread in the system than DV1 and DV2.

The DV1 does not create in-gap defect states and the resistances change slightly when compared with the pristine case. This behavior becomes more evident in Figs. 14. The Landau plateaus are more resilient in DV1 and the range of the bend resistance is of the same order of magnitude as in the pristine case, while for MV and DV2 the bend resistances are higher. Further, one can see that the presence of the defects with broken symmetry actually suppress the scattering effect provoked by the zigzag transport modes. Analyzing Fig. 15, one notices that the increase in the longitudinal resistance  $R_{24,24}$  at ~ 9.3 T is smaller for MV and DV2, and also with the increase of density in DV1. Thus, one can infer that the presence of resonant states reduces the scattering provoked by the zigzag terminals. Apart from these specific effects, the general behavior is that the MV and DV2 enhances the resistances between two axial terminals. This behavior is in agreement with Ref.<sup>21</sup>. To better understand this effect we show in Fig. 16 the local density of the transport modes for a system with MV, DV1, and DV2 defects for  $n_x = 0.01\%$  and 0.05% and magnetic field B = 10 T. As the density is increased the modes are scattered to nonaxial terminals, which is reflected by the enhancement of the longitudinal resistance.



FIG. 14. The magnetic-field dependency of the Hall and bend resistances for the phosphorene Hall bar with vacancies at fixed Fermi energy  $E_F = 0.35$  eV.

## V. CONCLUSIONS

In summary we analyzed the electrical transport properties of a phosphorene Hall bar in the presence of a magnetic field and vacancy defects. The presence of axial and non axial terminals, with different characteris-



FIG. 15. The magnetic-field dependency of the longitudinal resistance for the phosphorene Hall bar with vacancies at fixed Fermi energy  $E_F = 0.35$  eV.

tics, allowed us to study different transport properties of phosphorene material<sup>21,37</sup> (in this case, the Hall and longitudinal resistances). In Sec. III, we studied the pristine system where a ballistic regime was identified by the bend resistance to certain regimes of Fermi energy and magnetic field, and Landau plateaus show up in the Hall resistance mainly due the semiconductor features of the armchair terminals<sup>8,21</sup>. This can be seen for magnetoresistance for  $E_F = 0.363$  eV which matches a zigzag transport mode (see Fig. 5) and shows no Landau plateaus for the Hall resistance (see Fig. 10). Also, as stated in Ref. [<sup>21</sup>], the presence of zigzag transport modes provokes scattering of the transport modes, resulting in a larger peak in the resistance as the Fermi energy crosses the zigzag Landau level, see Fig. 11.

The presence of vacancies changes the magneto transport properties, depending on the sublattice symmetry and on the vacancy density, as shown in Sec. IV. The effects on the resistance are most noticeable for vacancy types with broken sublattice symmetry, with the MV being the one that most affects the resistance. Although DV1 does not create in-gap states (as shown in Fig. 12) the defects still affect the phosphorene transport properties. When analyzing the magnetoresistance, a change in the sign of the bend resistance appears, which indicates a diffusive regime induced by scattering from the defects. The present paper clearly indicates the much richer transport features that can be observed in phosphorene as compared to graphene. The anisotropy of the phosphorene lattice and the presence of a gap are responsible for the increased complexity of its electrical response.



FIG. 16. Current density for the phosphorene Hall bar with vacancy defects MV(a), DV1(b), and DV2(c) for  $n_x = 0.01\%$  and MV(d), DV1(e) and DV2(f) for  $n_x = 0.05\%$ . We fixed  $E_F = 0.35$  eV and B = 10 T.

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